

<IGBT Modules>

## **CM400DY-13T**

HIGH POWER SWITCHING USE INSULATED TYPE



dual switch (half-bridge)

1 7 5 °C

- •Flat base type
- Nickel-plating tab terminals
- •RoHS Directive compliant
- •UL Recognized under UL1557, File No.E323585

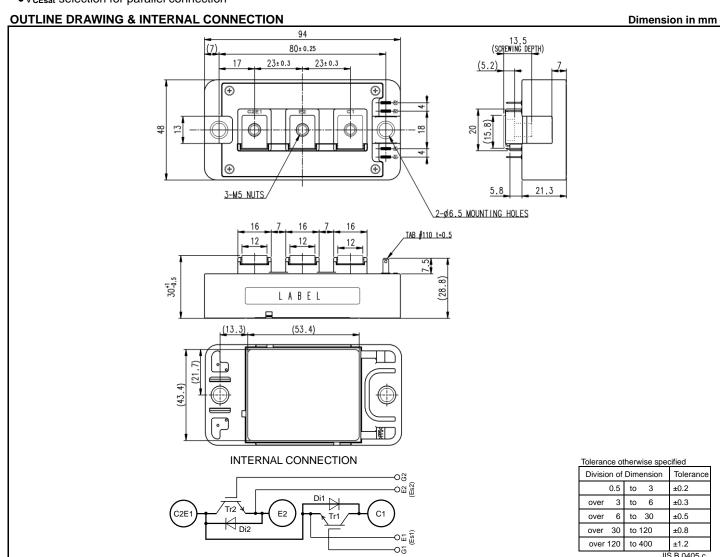
Maximum junction temperature T<sub>vjmax</sub> .......

#### **APPLICATION**

AC Motor Control, Motion/Servo Control, Power supply, etc.

**OPTION** (Below options are available.)

- ullet PC-TIM (Phase Change Thermal Interface Material) pre-apply (Note8)
- Vcesat selection for parallel connection



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### MAXIMUM RATINGS ( $T_{vj}$ =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	650	V	
$V_{GES}$	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Callactor ourset	DC, T <sub>C</sub> =140 °C* (Note2, 4)	400	^	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	800	Α	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	2830	W	
I <sub>E</sub> (Note1)	Finalista in accompany	DC (Note2)	400	^	
I <sub>ERM</sub> (Note1)	Emitter current	Pulse, Repetitive (Note3)	800	A	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T <sub>vjmax</sub>	Maximum junction temperature	Instantaneous event (overload) (Note8)	175	°C	
T <sub>Cmax</sub>	Maximum case temperature	(Note4,8)	150*		
T <sub>vjop</sub>	Operating junction temperature	Continuous operation (under switching) (Note8)	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +150*		

### ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Complete		Conditions	Conditions		Limits		
Symbol	Item	item Conditions		Min.	Тур.	Max.	Unit
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	-	1.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	0.5	μΑ
$V_{GE(th)}$	Gate-emitter threshold voltage	I <sub>C</sub> =40 mA, V <sub>CE</sub> =10 V		5.4	6.0	6.6	V
		I <sub>C</sub> =400 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	1.45	1.75	V
V <sub>CEsat</sub>		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	1.55	-	
(Terminal)	Callantar arrittar anti-matica valtara	(Note5)	T <sub>vj</sub> =150 °C	-	1.60	-	
	Collector-emitter saturation voltage	I <sub>C</sub> =400 A,	T <sub>vj</sub> =25 °C	-	1.30	1.55	
V <sub>CEsat</sub>		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	1.35	-	V
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.35	-	
Cies	Input capacitance			-	-	53.5	
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		-	-	2.6	nF
Cres	Reverse transfer capacitance	,		-	-	1.0	
Q <sub>G</sub>	Gate charge	Vcc=300 V, Ic=400 A, VgE=15 V		-	1.65	-	μC
t <sub>d(on)</sub>	Turn-on delay time	V <sub>CC</sub> =300 V, I <sub>C</sub> =400 A, V <sub>GE</sub> =±15 V,  R <sub>G</sub> =1.6 Ω, Inductive load		-	-	400	- ns
tr	Rise time			-	-	200	
t <sub>d(off)</sub>	Turn-off delay time			-	-	400	
tf	Fall time			-	-	400	
		I <sub>E</sub> =400 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	2.10	2.90	
V <sub>EC</sub> (Note.1)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.05	-	V
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.05	-	
	V <sub>EC</sub> (Note.1) (Chip)	I <sub>E</sub> =400 A,	T <sub>vj</sub> =25 °C	-	1.90	2.65	
		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	1.80	-	V
(Cnip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.80	-	
t <sub>rr</sub> (Note1)	Reverse recovery time	V <sub>CC</sub> =300 V, I <sub>E</sub> =400 A, V <sub>GE</sub> =±15 V,		-	-	200	ns
Q <sub>rr</sub> (Note1)	Reverse recovery charge	$R_G=1.6 \Omega$ , Inductive load		-	14	-	μC
Eon	Turn-on switching energy per pulse	V <sub>CC</sub> =300 V, I <sub>C</sub> =I <sub>E</sub> =400 A,		-	4.5	-	1
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}=\pm 15 \text{ V}, R_{G}=1.6 \Omega, T_{vj}=150 ^{\circ}\text{C},$		-	21.6	-	mJ
E <sub>rr</sub> (Note1)	Reverse recovery energy per pulse	Inductive load		-	9.0	-	mJ
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25 °C (Note4)		-	0.3	-	mΩ
r <sub>g</sub>	Internal gate resistance	Per switch		-	1.5	-	Ω

<sup>\*:</sup> The value of PC-TIM applied module is limited by the heat resistant temperature of PC-TIM.

### HIGH POWER SWITCHING USE

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#### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Itam	Conditions	Limits			Unit
	ltem	Conditions	Min.	Тур.	Max.	Unit
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	53	K/kW
R <sub>th(j-c)D</sub>		Junction to case, per Inverter FWD (Note4)	-	-	84	I K/KVV
R <sub>th(c-s)</sub>	Contact thermal resistance	Case to heat sink, per 1 module  Thermal grease applied (Note4,6,8)	-	24	-	K/kW

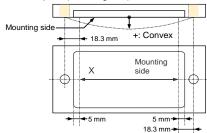
#### **MECHANICAL CHARACTERISTICS**

Symbol	Item	Conditions		Limits		Unit	
	item	Conditions		Min.	Тур.	Max.	Unit
M <sub>t</sub>	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
۵	Creepage distance	Terminal to terminal		18	-	-	mm
d <sub>s</sub>		Terminal to base plate		21.1	-	-	
d	Clearance	Terminal to terminal		9.6	-	-	
da	Clearance	Terminal to base plate		16.7	-	-	mm
ec	Flatness of base plate	On the centerline (Note7)		±0	-	+200	μm
m	mass	-		-	155	-	g

<sup>\*.</sup> This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU and (EU) 2015/863.

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).

- 2. Junction temperature (T  $_{\nu\,j})$  should not increase beyond T  $_{\nu\,j\,m\,a\,x}$  rating.
- 3. Pulse width and repetition rate should be such that the device junction temperature (T<sub>vj</sub>) dose not exceed T<sub>vjmax</sub> rating.
- 4. Case temperature (T<sub>C</sub>) and heat sink temperature (T<sub>S</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
- 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
- 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =3.0 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
- 7. The base plate (mounting side) flatness measurement points (X) are shown in the following figure.



8. Long term performance related to thermal conductive grease and PC-TIM (including but not limited to aspects such as the increase of thermal resistance due to pumping out, etc.) should be verified under your specific application conditions. Each temperature condition (T<sub>vj max</sub>, T<sub>vj op</sub>, T<sub>C max</sub>) must be maintained below the maximum rated temperature throughout consideration of the temperature rise even for long term usage.

HIGH POWER SWITCHING USE

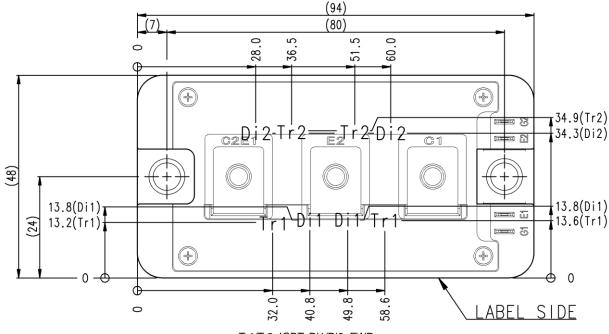
**INSULATED TYPE** 

### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Item	Conditions	Limits			Unit
	item		Min.	Тур.	Max.	Unit
V <sub>cc</sub>	(DC) Supply voltage	Applied across C1-E2 terminals	-	300	450	V
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	1.6	-	16	Ω

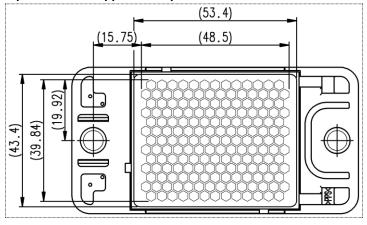
### **CHIP LOCATION (Top view)**

Dimension in mm, tolerance: ±1 mm

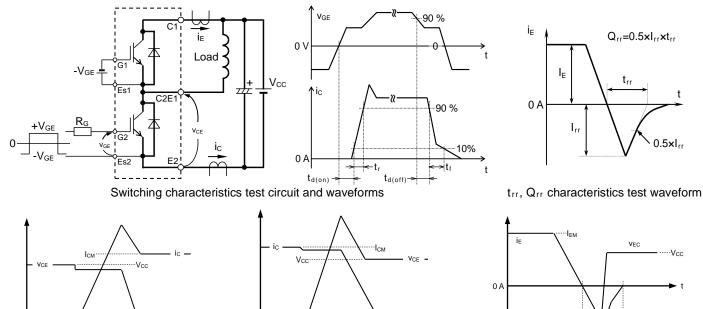


Tr1/Tr2: IGBT, Di1/Di2: FWD

### Option: PC-TIM applied baseplate outline



### **TEST CIRCUIT AND WAVEFORMS**



IGBT Turn-on switching energy

IGBT Turn-off switching energy

0.02×IcN

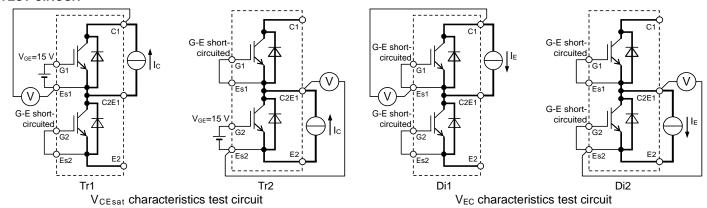
0 V

0.1xVc

FWD Reverse recovery energy

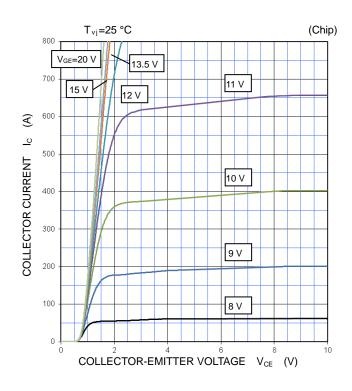
Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

#### **TEST CIRCUIT**

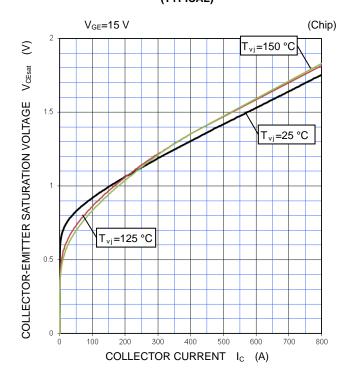


#### **PERFORMANCE CURVES**

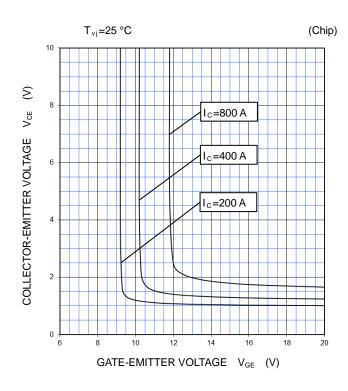
## OUTPUT CHARACTERISTICS (TYPICAL)



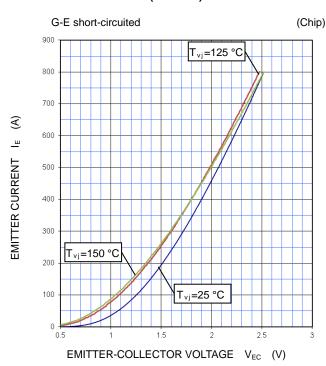
#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



## COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS (TYPICAL)



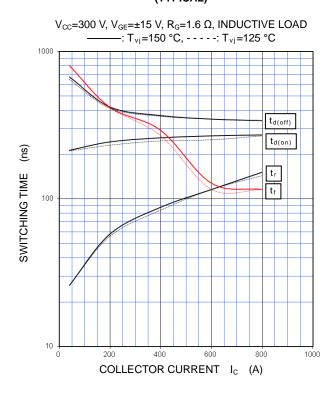
#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)



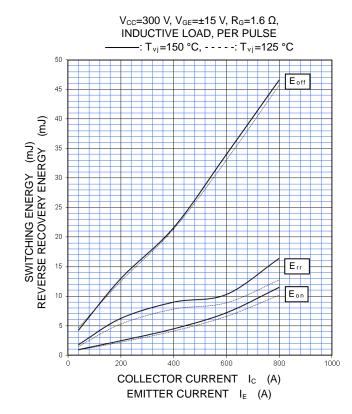
HIGH POWER SWITCHING USE INSULATED TYPE

#### **PERFORMANCE CURVES**

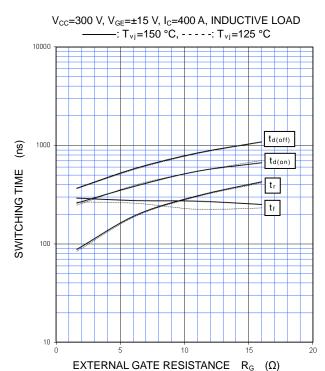
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



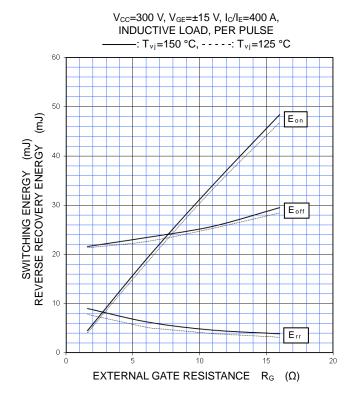
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



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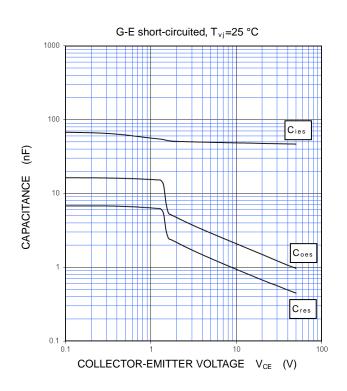
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



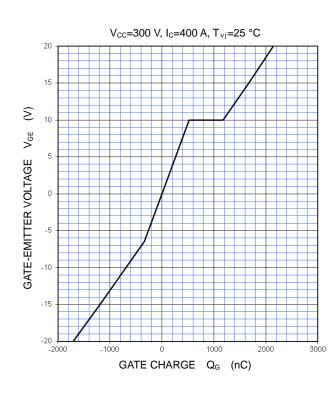
### INSULATED TYPE

#### **PERFORMANCE CURVES**

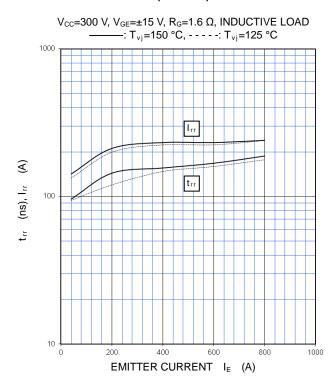
## CAPACITANCE CHARACTERISTICS (TYPICAL)



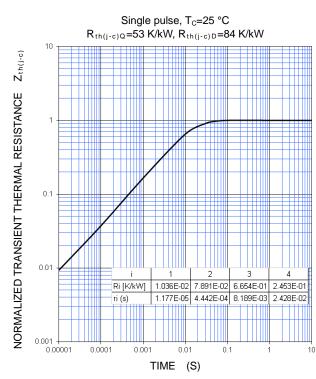
## GATE CHARGE CHARACTERISTICS (TYPICAL)



# FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



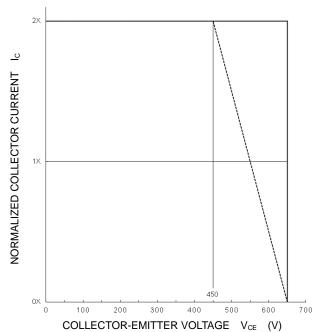
## TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



#### **PERFORMANCE CURVES**

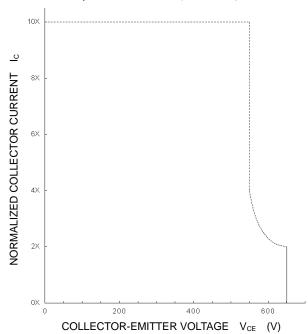
#### TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)

 $V_{CC}$ ≤450 V,  $V_{GE}$ =±15 V,  $R_G$ =1.6~16 Ω,
——:  $T_{vj}$ =25~150 °C (Normal load operations (Continuous)
-----:  $T_{vj}$ =175 °C (Unusual load operations (Limited period)



## SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)

 $V_{CC} \le 400$  V,  $V_{GE} = \pm 15$  V,  $R_G = 1.6 \sim 16$   $\Omega$ ,  $T_{vj} = 25 \sim 150$  °C,  $t_W \le 8$   $\mu$ s, Non-Repetitive



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

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